

Search Notes

Application/Control No.

10/057,672

Examiner

Djenane M. Bayard

Applicant(s)/Patent under
Reexamination

CLANCY ET AL.

Art Unit

2141

SEARCHED

Class	Subclass	Date	Examiner
709	225	10/27/2005	DB
709	235	10/27/2005	DB
709	227	10/27/2005	DB
709	228	10/27/2005	DB

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
709	225/235	10/27/2005	DB
709	227/228	10/27/2005	DB

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	10/27/2005	DB
Inventor's search	10/27/2005	DB
Consulted with Lee Luu	10/27/2005	DB
NPL search (IEEE, google, stic)	10/27/2005	db